R&S®RTO Digital Oscilloscope Specifications







Data Sheet | 18.00

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Definitions

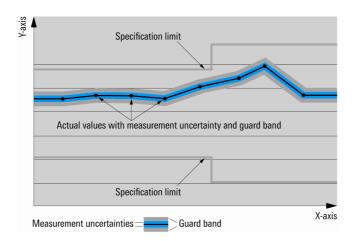
General

Product data applies under the following conditions:

- · Three hours storage at ambient temperature followed by 30 minutes warm-up operation
- Specified environmental conditions met
- · Recommended calibration interval adhered to
- All internal automatic adjustments performed, if applicable

Specifications with limits

Represent warranted product performance by means of a range of values for the specified parameter. These specifications are marked with limiting symbols such as <, \leq , >, \geq , \pm , or descriptions such as maximum, limit of, minimum. Compliance is ensured by testing or is derived from the design. Test limits are narrowed by guard bands to take into account measurement uncertainties, drift and aging, if applicable.



Specifications without limits

Represent warranted product performance for the specified parameter. These specifications are not specially marked and represent values with no or negligible deviations from the given value (e.g. dimensions or resolution of a setting parameter). Compliance is ensured by design.

Typical data (typ.)

Characterizes product performance by means of representative information for the given parameter. When marked with <, > or as a range, it represents the performance met by approximately 80 % of the instruments at production time. Otherwise, it represents the mean value.

Nominal values (nom.)

Characterize product performance by means of a representative value for the given parameter (e.g. nominal impedance). In contrast to typical data, a statistical evaluation does not take place and the parameter is not tested during production.

Measured values (meas.)

Characterize expected product performance by means of measurement results gained from individual samples.

Uncertainties

Represent limits of measurement uncertainty for a given measurand. Uncertainty is defined with a coverage factor of 2 and has been calculated in line with the rules of the Guide to the Expression of Uncertainty in Measurement (GUM), taking into account environmental conditions, aging, wear and tear.

Device settings and GUI parameters are indicated as follows: "parameter: value".

Typical data as well as nominal and measured values are not warranted by Rohde & Schwarz.

Base unit

Vertical system

vortiour cycloni		
Input channels	R&S®RTO1002	2 channels
	R&S®RTO1004	4 channels
	R&S®RTO1012	2 channels
	R&S®RTO1014	4 channels
	R&S®RTO1022	2 channels
	R&S®RTO1024	4 channels
	R&S®RTO1044	4 channels
Input impedance		50 Ω ± 2 %
p p		$(50 \Omega \pm 1.5 \% \text{ from } +15 ^{\circ}\text{C to } +30 ^{\circ}\text{C}),$
		$1 M\Omega \pm 1 \% 15 pF (meas.)$
Analog bandwidth (–3 dB)	at 50 Ω input impedance	
	R&S®RTO1002 and R&S®RTO1004	≥ 600 MHz
	R&S®RTO1012 and R&S®RTO1014	≥ 1 GHz
	R&S®RTO1022 and R&S®RTO1024	≥ 2 GHz
	R&S®RTO1044	≥ 4 GHz
	at 1 MΩ input impedance	≥ 500 MHz (meas.)
Analog bandwidth limits	max. –1.5 dB, min. –4 dB	200 MHz, 20 MHz
Rise time/fall time	10 % to 90 % at 50 Ω (calculated)	200 1111 12, 20 1111 12
Tibe unichan unic	R&S®RTO1002 and R&S®RTO1004	583 ps
	R&S®RTO1012 and R&S®RTO1014	350 ps
	R&S®RTO1022 and R&S®RTO1024	175 ps
	R&S®RTO1044	100 ps
Input VSWR	input frequency ≤ 2 GHz	1.25 (meas.)
Input vovik	input frequency > 2 GHz	1.4 (meas.)
Vertical resolution	input frequency > 2 GHz	8 bit,
vertical resolution		16 bit for high resolution decimation (with
		reduction of the sampling rate),
		16 bit for high definition mode (without
		reduction of the sampling rate, requires
Effective number of hits of digitizer	for full goals give wave signal with	the option R&S®RTO-K17) > 7.0 bit (meas.)
Effective number of bits of digitizer	for full-scale sine-wave signal with	> 7.0 bit (meas.)
	frequency equal to or lower than –3 dB bandwidth	
DC gain accuracy	offset and position set to 0 V, after self-ali	gnment
,	at 50 Ω, input sensitivity > 5 mV/div	±1.5 %
	at 50 Ω, input sensitivity ≤ 5 mV/div	±2 %
	at 1 MΩ	±2 %
Input coupling	at 50 Ω	DC and GND
	at 1 MΩ	DC, AC and GND
Input sensitivity	at 50 Ω	1 mV/div to 1 V/div
mpat conditivity	at 1 MΩ	1 mV/div to 10 V/div
Maximum input voltage	at 50 Ω	5 V (RMS)
maximum input voitage	at 1 MΩ	150 V (RMS), 200 V (V _p),
	GC 1 1V132	derates at 20 dB/decade to 5 V (RMS)
		above 250 kHz
Position range		±5 div
Offset range at 50 Ω	input sensitivity	±5 div
Onset range at 50 12	316 mV/div to ≤ 1 V/div	±10 V
	100 mV/div to ≤ 316 mV/div	±3 V
Offset range at 1 MO	1 mV/div to ≤ 100 mV/div	±1 V
Offset range at 1 MΩ	input sensitivity	1/44E V input constitute of 5 dt A
	3.16 V/div to ≤ 10 V/div	±(115 V – input sensitivity × 5 div)
	1 V/div to ≤ 3.16 V/div	±100 V
	316 mV/div to ≤ 1 V/div	±(11.5 V – input sensitivity × 5 div)
	100 mV/div to ≤ 316 mV/div	±10 V
	31.6 mV/div to ≤ 100 mV/div	±(1.15 V – input sensitivity × 5 div)
	1 mV/div to ≤ 31.6 mV/div	±1 V
Offset accuracy		±(0.35 % × net offset +
-		2.5 mV + 0.1 div × input sensitivity)
		(net offset =

DC measurement accuracy	after adequate suppression of	±(DC gain accurac	y ×
	measurement noise using high-resolution	reading – net offset	
	sampling mode or waveform averaging or	+ offset accuracy)	
	a combination of both		
Channel-to-channel isolation	input frequency ≤ 2 GHz	> 60 dB	
(each channel at same input sensitivity)	input frequency > 2 GHz	> 50 dB	
RMS noise floor at 50 Ω (typ.)	input sensitivity	R&S®RTO1002,	R&S®RTO1012,
		R&S®RTO1004	R&S®RTO1014
	1 mV/div	0.08 mV	0.10 mV
	2 mV/div	0.08 mV	0.10 mV
	5 mV/div	0.11 mV	0.12 mV
	10 mV/div	0.17 mV	0.20 mV
	20 mV/div	0.28 mV	0.36 mV
	50 mV/div	0.70 mV	0.85 mV
	100 mV/div	1.30 mV	1.65 mV
	200 mV/div	2.70 mV	3.30 mV
	500 mV/div	7.00 mV	8.70 mV
	1 V/div	13.7 mV	17.0 mV
	input sensitivity	R&S®RTO1022,	R&S®RTO1044
		R&S®RTO1024	(meas.)
	1 mV/div	0.15 mV	0.24 mV
	2 mV/div	0.15 mV	0.25 mV
	5 mV/div	0.18 mV	0.28 mV
	10 mV/div	0.28 mV	0.42 mV
	20 mV/div	0.50 mV	0.72 mV
	50 mV/div	1.22 mV	1.80 mV
	100 mV/div	2.39 mV	3.60 mV
	200 mV/div	4.80 mV	7.20 mV
	500 mV/div	12.0 mV	18.0 mV
	1 V/div	23.9 mV	36.0 mV

Horizontal system

Timebase range		selectable between 25 ps/div and 50 s/div,
		time per div settable to any value within
		range
Channel deskew		±100 ns
Reference position		10 % to 90 % of measurement display
		area
Trigger offset range	max.	+(memory depth/current sampling rate)
	min.	-10 000 s
Modes		normal, roll
Channel-to-channel skew		< 100 ps (meas.)
Timebase accuracy	standard	
	after delivery/calibration, at +23 °C	±5 ppm
	during calibration interval	±10 ppm
	with R&S®RTO-B4 option	
	after delivery/calibration, at +23 °C	±0.02 ppm
	during calibration interval	±0.2 ppm
	long-term stability	±(0.1 + 0.1 × years since calibration) ppm
	(more than one year since calibration)	
Delta time accuracy	corresponds to time error between two	±(K/realtime sampling rate +
	edges on same acquisition and channel;	timebase accuracy × reading) (peak)
	signal amplitude greater than 5 divisions,	(meas.)
	measurement threshold set to 50 %,	where
	vertical gain 10 mV/div or greater; rise	K = 0.15 (R&S [®] RTO1002, R&S [®] RTO1004)
	time lower than four sample periods;	K = 0.18 (R&S [®] RTO1012, R&S [®] RTO1014)
	waveform acquired in realtime mode	K = 0.25 (R&S [®] RTO1022, R&S [®] RTO1024) K = 0.43 (R&S [®] RTO1044)

Acquisition system

Realtime sampling rate	R&S®RTO1002, R&S®RTO1004,	max. 10 Gsample/s on each channel
, ,	R&S®RTO1012, R&S®RTO1014,	
	R&S®RTO1022, R&S®RTO1024	
	R&S®RTO1044	max. 10 Gsample/s on 4 channels,
		max. 20 Gsample/s on 2 channels
Realtime waveform acquisition rate	max.	> 1 000 000 waveforms/s
Memory depth	standard	1 000 000 1101 0101 1107 0
Welliofy depth	R&S®RTO1002, R&S®RTO1012,	20 Msample on 2 channels,
	R&S®RTO1002, N&S 101012,	40 Msample on 1 channel
	R&S®RTO1022 R&S®RTO1004, R&S®RTO1014,	· · · · · · · · · · · · · · · · · · ·
		20 Msample on 4 channels,
	R&S [®] RTO1024, R&S [®] RTO1044	40 Msample on 2 channels,
		80 Msample on 1 channel
	R&S®RTO-B101 option	
	R&S®RTO1002, R&S®RTO1012,	50 Msample on 2 channels,
	R&S®RTO1022	100 Msample on 1 channel
	R&S®RTO1004, R&S®RTO1014,	50 Msample on 4 channels,
	R&S®RTO1024, R&S®RTO1044	100 Msample on 2 channels,
		200 Msample on 1 channel
	R&S®RTO-B102 option	
	R&S®RTO1002, R&S®RTO1012,	100 Msample on 2 channels,
	R&S®RTO1022	200 Msample on 1 channel
	R&S®RTO1004, R&S®RTO1014,	100 Msample on 4 channels,
	R&S®RTO1024, R&S®RTO1044	200 Msample on 2 channels,
	1103 11101024, 1103 11101044	400 Msample on 1 channel
	DOC®DIO D102 ention (instruments wit	
		h operating system Windows 7 embedded)
	R&S®RTO1002, R&S®RTO1012,	200 Msample on 2 channels,
	R&S®RTO1022	400 Msample on 1 channel
	R&S [®] RTO1004, R&S [®] RTO1014,	200 Msample on 4 channels,
	R&S®RTO1024, R&S®RTO1044	400 Msample on 2 channels,
		800 Msample on 1 channel
	R&S®RTO-B104 option (instruments	with operating system Windows 7 embedded)
	R&S [®] RTO1002, R&S [®] RTO1012,	400 Msample on 2 channels,
	R&S®RTO1022	800 Msample on 1 channel
	R&S®RTO1004, R&S®RTO1014,	400 Msample on 4 channels,
	R&S®RTO1024, R&S®RTO1044	800 Msample on 2 channels (restriction:
	,	400 Msample on 2 channels when Ch1
		and Ch2 or Ch3 and Ch4 are turned on),
		800 Msample on 1 channel
Decimation modes	sample	first sample in decimation interval
Decimation modes	peak detect	largest and smallest sample in decimation
	peak detect	
	hinh need wien	interval
	high resolution	average value of samples in decimation
		interval
	root mean square	root of squared average of samples in
		decimation interval
Waveform arithmetic	off	no arithmetic
	envelope	envelope of acquired waveforms
	average	average of acquired waveforms,
	-	max. average depth depends on
		decimation mode ¹
	sample	max. 16 777 215
	high resolution	max. 65 535
		max. 255
	root mean square	
	reset condition	no reset (standard), reset by time, reset by
		number of processed waveforms
Waveform streams per channel		up to 3 with independent selection of
		decimation mode and waveform arithmetic

¹ Waveform averaging is not compatible with peak detect decimation.

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Sampling modes	realtime mode	max. sampling rate set by digitizer
	interpolated time	enhancement of sampling resolution by
		interpolation; max. equivalent sampling
		rate is 4 Tsample/s
	equivalent time	enhancement of sampling resolution by
		repetitive acquisition; max. equivalent
		sampling rate is 4 Tsample/s
Interpolation modes		linear, sin(x)/x, sample&hold
Ultra segmented mode		continuous recording of waveforms in
		acquisition memory without interruption
		due to visualization; blind time between
		consecutive acquisitions less than 300 ns

Trigger system

Sources	R&S®RTO1002, R&S®RTO1012,	channel 1, channel 2
	R&S®RTO1022	
	R&S®RTO1004, R&S®RTO1014,	channel 1, channel 2, channel 3, channel 4
	R&S®RTO1024, R&S®RTO1044	
Sensitivity	trigger hysteresis mode	auto (standard) or manual
	range	0 V to 5 div × input sensitivity
Trigger jitter	full-scale sine wave of frequency set to	< 1 ps (RMS) (meas.)
,	-3 dB bandwidth	
Coupling mode	standard	same as selected channel
	lowpass filter	cutoff frequency selectable from 100 kHz
		to 50 % of analog bandwidth
Sweep mode		auto, normal, single, n single
Event rate	max.	one event for every 400 ps time interval
Trigger level	range	±5 div from center of screen
Holdoff range	time	100 ns to 10 s, fixed and random
	events	1 event to 2 000 000 000 events

Main trigger modes				
Edge	triggers on specified slope (posit	tive, negative or either) and level		
Glitch	triggers on glitches of positive, n specified width	triggers on glitches of positive, negative or either polarity that are shorter or longer than specified width		
	glitch width	100 ps to 1000 s		
		50 ps to 1000 s (R&S®RTO1044 only)		
Width	triggers on positive or negative prinside or outside the interval	oulse of specified width; width can be shorter, longer,		
	pulse width	100 ps to 1000 s		
	, , , , , ,	50 ps to 1000 s (R&S®RTO1044 only)		
Runt	triggers on pulse of positive, neo	gative or either polarity that crosses one threshold but		
		before crossing the first one again; runt pulse width		
	can be arbitrary, shorter, longer,			
	runt pulse width	100 ps to 1000 s		
	, and passes	50 ps to 1000 s (R&S®RTO1044 only)		
Window		xits a specified voltage range; triggers also when signal ge range for a specified period of time		
Timeout		low or unchanged for a specified period of time		
rimedat	timeout	100 ps to 1000 s		
	umodi	50 ps to 1000 s (R&S®RTO1044 only)		
Interval	triggers when time between two	triggers when time between two consecutive edges of same slope (positive or negative)		
ilitei vai	is shorter, longer, inside or outsi			
	interval time	100 ps to 1000 s		
	mervar time	50 ps to 1000 s (R&S®RTO1044 only)		
Slew rate	triggers when the time required by a signal edge to toggle between user-defined upper			
Olew rate	and lower voltage levels is shorter, longer, inside or outside the interval; edge slope			
	may be positive, negative or either			
	toggle time	100 ps to 1000 s		
	toggie time	50 ps to 1000 s (R&S®RTO1044 only)		
Data2clock	triggers on setup time and hold t	time violations between clock and data present on any		
Datazolock		two input channels; monitored time interval may be specified by the user in the range		
	· ·	a clock edge and must be at least 100 ps wide		
Pattern		tion (and, nand, or, nor) of the input channels stays true		
		er, inside or outside a specified range		
State		triggers when a logical combination (and, nand, or, nor) of the input channels stays true		
		at a slope (positive, negative or either) in one selected channel		
Serial pattern		triggers on serial data pattern up to 128 bit clocked by one input channel; pattern bits		
Conai pattorn	may be high (H), low (L) or don't care (X); clock edge slope may be positive, negative			
	or either; hardware CDR selectable as clock source (requires R&S®RTO-K13 option)			
	max. data rate	< 2.50 Gbps		
		< 5 Gbps (R&S®RTO1044 only)		
TV/video	triggers on baseband analog pro	triggers on baseband analog progressive and interlaced video signals including NTSC,		
,	PAL, PAL-M, SECAM, EDTV and HDTV broadcast standards as well as custom bi-level			
	and tri-level sync video standards			
	trigger modes	all fields, odd fields, even fields, all lines,		
	tilgger modes	line number		

Advanced trigger modes			
Trigger qualification	trigger events may be qualified by a logical		
	qualifiable events	edge, glitch, width, runt, window, timeout, interval	
Sequence trigger (A/B/R trigger)	triggers on B event after occurrence of A event; delay condition after A event specified either as time interval or number of B events; an optional R event resets the trigger sequence to A		
	A event	any trigger mode	
	B event	edge	
	R event	edge, glitch, width, runt, window, timeout, interval, slew rate	
Serial bus trigger	basic	I ² C, SPI, UART/RS-232	
	optional	LIN, CAN, FlexRay™ and I²S with dedicated software options	
NFC trigger		with R&S®RTO-K11 option	
CDR trigger	triggers on clock signal recovered from the instant user-selectable as fraction of bit per CDR configuration parameters	trigger source signal; phase of the trigger	
	CDR bit rate range	pg,	
	R&S®RTO1002, R&S®RTO1004, R&S®RTO1012, R&S®RTO1014, R&S®RTO1022, R&S®RTO1024	200 kbps to 2.5 Gbps	
	R&S®RTO1044	200 kbps to 2.5 Gpbs standard, 400 kbps to 5.0 Gbps when operating at 20 Gsample/s realtime sampling rate ²	
External trigger input	input impedance	$50 \Omega \pm 1.5 \%$ or $1 M\Omega \pm 1 \% \parallel 20 pF (meas.)$	
	max. input voltage at 50 Ω	5 V (RMS)	
	max. input voltage at 1 $M\Omega$	30 V (RMS) derates at 20 dB/decade to 5 V (RMS) above 25 MHz	
	trigger level	±5 V	
	sensitivity	1 == :	
	input frequency ≤ 100 MHz	300 mV (V _{pp})	
	100 MHz < input frequency ≤ 500 MHz	600 mV (V _{pp})	
	input coupling	AC, DC (50 Ω and 1 MΩ), GND, HF reject (attenuates > 50 kHz or > 50 MHz, user-selectable), LF reject (attenuates < 5 kHz or < 50 kHz user-selectable)	
	trigger modes	edge (rise or fall)	
Trigger out	functionality	a pulse is generated for every acquisition trigger event	
	output voltage	0 V to 5 V at high impedance; 0 V to 2.5 V at 50 Ω	
	pulse width	selectable between 50 ns and 60 ms	
	pulse polarity	low active or high active	
	output delay	depends on trigger settings	
	iitter	±600 ps (meas.)	

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² The R&S®RTO1044 front-end samples at 20 Gsample/s when at most one channel from each pair {channel1, channel2} and {channel3, channel4} is active; and the user-selected sampling resolution in realtime sampling mode or interpolated time sampling mode is 50 ps or smaller.

Waveform measurements

General features	measurement panels	up to 8 measurement panels; each panel may contain any number of automatic
		measurements of the same category
	gate	delimits the display region evaluated for
	3	automatic measurements
	reference levels	user-configurable vertical levels define
	1010101100 101010	support structures for automatic
		measurements
	statistics	displays maximum, minimum, mean,
	Stationos	standard deviation, RMS and
		measurement count for each automatic
		measurement
	track	measurement results displayed as
	llaok	continuous trace that is time-correlated to
		the measurement source; requires
		· · · · · · · · · · · · · · · · · · ·
	lang term analysis	R&S®RTO-K12 option
	long-term analysis	history of selected measurements as trace
	historyaya	against count index
	histogram	available for one measurement per
	P. 11. 1	measurement panel
	limit check	measurements tested against user-defined
		margins and limits; pass or fail conditions
		may launch automatic response:
		acquisition stop, beep, print and save
		waveform
Measurement category	amplitude and time	amplitude, high, low, maximum, minimum,
		peak-to-peak, mean, RMS, sigma,
		overshoot, area, rise time, fall time,
		positive width, negative width, period,
		frequency, duty cycle, delay, phase, burst
		width, pulse count, positive switching,
		negative switching, cycle area, cycle
		mean, cycle RMS, cycle sigma, setup/hold
		time, setup/hold ratio, pulse train,
		DC voltmeter (requires Rohde & Schwarz
		active probe with R&S®ProbeMeter
		functionality)
	eye diagram	extinction ratio, eye height, eye width, eye
		top, eye base, Q factor, S/N ratio, duty
		cycle distortion, eye rise time, eye fall
		time, eye bit rate, eye amplitude, jitter
		(peak-to-peak, 6-sigma, RMS)
	spectrum	channel power, bandwidth, occupied
		bandwidth, total harmonic distortion
	jitter	cycle-to-cycle jitter, N-cycle jitter, cycle-to-
	Jittei	cycle width, cycle-to-cycle duty cycle,
		time-interval error, data rate, unit interval,
		skew delay, skew phase; requires R&S®RTO-K12 option
Cureore	sotup	
Cursors	setup	up to 4 cursor sets on screen, each set
		consisting of two horizontal and two
	An war of	vertical cursors
	target	acquired waveforms (input channels),
		math waveforms, reference waveforms,
		track waveforms, XY diagrams
	operating mode	vertical measurements, horizontal
		measurements or both;
		vertical cursors either set manually or
		locked to waveform

Histogram	source	acquired waveform (input channels),
		math waveform, reference waveform
	mode	vertical (for timing statistics), horizontal
		(for amplitude statistics)
	automatic measurements	waveform count, waveform samples,
		histogram samples, histogram peak,
		peak value, maximum, minimum, median,
		range, mean, sigma, mean ± 1, 2 and 3
		sigma, marker ± probability

Mask testing

Test definition	number of masks	up to 8 simultaneously	
	source	acquired waveforms (input channels),	
		math waveforms	
	fail condition	sample hit or waveform hit	
	fail tolerance	minimum number of fail events for test fail	
		in range from 0 to 4 000 000 000	
	test rate	up to 600 000 waveforms per second	
	action on error	acquisition stop, beep, print and save	
		waveform	
	save/load to file	test and mask settings (.xml format)	
Mask definition with segments	number of independent segments	up to 8	
	segment definition	array of points and connecting rule (upper, lower, inner) define segment region	
	segment input	point and click on touchscreen, editable list	
Mask definition with tolerance tube	input signal	acquired waveform	
	definition of tolerance tube	horizontal width, vertical width, vertical	
		stretch, vertical position	
Mask definition with eye mask assistant	primary mask shape		
(requires R&S®RTO-K12 option)	type	diamond, square, hexagon, octagon	
	dimensions	main and secondary height, main and	
		secondary width, depending on selected	
		shape	
	position	vertical offset, horizontal offset	
	secondary mask shapes		
	locations	any combination of left, right, top, bottom	
	position	horizontal and vertical offset with respect	
		to center of primary mask shape	
Result statistics	category	completed acquisitions, remaining	
		acquisitions, state, sample hits, mask hits,	
		fail rate, test result (pass or fail)	
Visualization options	waveform style	vectors, dots	
	violation highlighting	hits (on/off), highlight persistence	
		(50 ms to 50 s or infinite), waveform color	
		(default: red)	
	mask colors	configurable colors for mask without	
		violation (default: translucent gray), mask	
		with violation (default: translucent red),	
		mask with contact (default: translucent	
		pale red)	

Waveform math

General features	number of math waveforms	up to 4		
	number of reference waveforms	up to 4		
	waveform arithmetic	user-selectable average or envelope of consecutive waveforms		
Algebraic expressions	user may define complex mathematica	user may define complex mathematical expressions involving waveforms and		
	math functions	add, subtract, multiply, divide, absolute value, square, square root, integrate, differentiate, exp, log ₁₀ , log _e , log ₂ , rescale, sin, cos, tan, arcsin, arccos, arctan, sinh, cosh, tanh, autocorrelation, crosscorrelation		
	logical operators	not, and, nand, or, nor, xor, nxor		
	relational operators	Boolean result of =, \neq , >, <, \leq , \geq		
	frequency domain	spectral magnitude and phase, real and imaginary spectra, group delay		
	digital filter	lowpass, highpass		
	special functions	CDR transform; requires R&S®RTO-K12 option		
Optimized math	operators	add, subtract, multiply, invert, absolute value, differentiate, log ₁₀ , log _e , log ₂ , rescale, FIR, FFT magnitude		
Spectrum analysis	FFT magnitude spectrum			
	setup parameters	center frequency, frequency span, frame overlap, frame window (rectangular, Hamming, Hann, Blackman, Gaussian, Flattop, Kaiser Bessel), user-selectable spectrum averaging and envelope		

Search and mark function

General description	scans acquired waveforms for oc each occurrence	scans acquired waveforms for occurrence of a user-defined set of events and highlight each occurrence	
Basic setup	source	all physical input channels, math waveforms, reference waveforms	
	search panels	up to 8, where each panel may manage multiple event searches	
	search mode	manually triggered or continuous	
	search conditions		
	supported events	edge, glitch, width, runt, window, timeout,	
		interval, slew rate, data2clock, state	
	event configuration	identical to corresponding trigger event	
	event selection	single or multiple events on same source	
Search scope	mode	current waveform, gated time interval	
Result visualization	table		
	sort mode	horizontal position or vertical value	
	max. result count	specifies max. table size	
	zoom window	centered on highlighted event	

Display characteristics

Diagram types	Yt, XY, spectrum, long-term measurement	
Display interface configuration	display area can be split up into separate diagram areas by dragging and dropping signal icons; each diagram area can hold any number of signals; diagram areas may be stacked on top of each other and later accessed via the dynam	
	tab menu	
Signal bar	accommodates timebase settings, trigger settings and signal icons; signal bar may be docked to left or right side of display area or hidden	
Signal icon	each active waveform is represented by a separate signal icon on the signal bar; the signal icon displays the individual vertical and acquisition settings; a waveform can be minimized to its signal icon so that it appears as a realtime preview in miniature form; dialog boxes and measurement results may also be minimized to a signal icon	
Axis label	X-axis ticks and Y-axis ticks labeled with tick value and physical unit	
Diagram label	diagrams may be individually labeled with a descriptive user-defined name	
Diagram layout	grid, crosshair, axis labels and diagram label may be switched on and off separately	
Persistence	50 ms to 50 s, or infinite	
Zoom	user-defined zoom window provides vertical and horizontal zoom; each diagram area supports multiple zoom windows; touchscreen interface simplifies resize and drag operations on zoom window	
Signal colors	predefined or user-defined color tables for persistence display	

Input and output

Front		
Channel inputs		BNC-compatible, for details see "Vertical system"
	probe interface	auto-detection of passive probes, Rohde & Schwarz active probe interface
Auxiliary output		SMA connector, for future use
Probe compensation output	signal shape	rectangle, $V_{low} = 0 \text{ V}$, $V_{high} = 1 \text{ V}$ amplitude 1 V (V_{pp}) ± 5 %
	frequency	1 kHz ± 1 %
	impedance	50 Ω (nom.)
Ground jack		connected to ground
USB interface		2 ports, type A plug, version 2.0

Rear	
External trigger input	BNC,
	for details see "Trigger system"
Trigger out	BNC,
	for details see "Trigger system"
USB interface	2 ports, type A plug, version 2.0
LAN interface	RJ-45 connector,
	supports 10/100/1000BaseT
External monitor interface	DVI-D connector,
	output of scope display or extended
	desktop display
GPIB interface	see R&S®RTO-B10 option
Reference input	see R&S®RTO-B4 option
Reference output	see R&S®RTO-B4 option
Security slot	for standard Kensington style lock

General data

Display	type	10.4" LC TFT color display with
		touchscreen
	resolution	1024 × 768 pixel (XGA)

Temperature		
Temperature loading	operating temperature range	0 °C to +45 °C
_	storage temperature range	-40 °C to +70 °C
Climatic loading		+25° C/+40 °C at 85 % rel. humidity cyclic,
_		in line with IEC 60068-2-30

Altitude	
Operating	up to 3000 m above sea level
Non-operating	up to 4600 m above sea level

Mechanical resistance		
Vibration	sinusoidal	5 Hz to 150 Hz, max. 2 g at 55 Hz;
		0.5 g from 55 Hz to 150 Hz;
		in line with EN 60068-2-6
	random	10 Hz to 300 Hz,
		acceleration 1.2 g (RMS),
		in line with EN 60068-2-64
Shock		40 g shock spectrum,
		in line with MIL-STD-810E, method
		no. 516.4, procedure I

EMC		
RF emission	in line with EN 55011 class A, operation in residential, commercial and business areas or in small-size companies is not covered; therefore the instrument may not be operated in residential, commercial and business areas or in small-size companies unless additional measures are taken to ensure that EN 55011 class B is complied with	in line with CISPR 11/EN 55011 group 1 class A (for a shielded test setup); the instrument complies with the emission requirements stipulated by EN 55011, EN 61326-1 and EN 61326-2-1 class A, making the instrument suitable for use in industrial environments
Immunity		in line with IEC/EN 61326-1 table 2, immunity test requirements for industrial environment ³

Certifications	VDE-GS, cCSA _{US}
	'

Calibration interval	1 year

Power supply	
AC supply	100 V to 240 V at
	50 Hz to 60 Hz and 400 Hz,
	max. 5.5 A to 2.3 A,
	in line with MIL-PRF 28800F section 3.5
Power consumption	max. 450 W
Safety	in line with IEC 61010-1, EN 61010-1,
	CAN/CSA-C22.2 No. 61010-1-04,
	UL 61010-1

Mechanical data		
Dimensions	W×H×D	427 mm × 249 mm × 204 mm
		(16.81 in × 9.80 in × 8.03 in)
Weight	without options, nominal	9.6 kg (21.16 lb)

 $^{^3}$ Test criterion is displayed noise level within ±1 div for input sensitivity of 5 mV/div.

Options

R&S®RTO-B1

Mixed signal option, additional 16 logic channels

Vertical system

Input channels		16 logic channels (D0 to D15)
Arrangement of input channels		arranged in two logic probes with
		8 channels each, assignment of the logic
		probes to the channels (D0 to D7 or D8 to
		D15) is displayed on the probe
Input impedance		100 kΩ ± 2 % ~4 pF (meas.) at probe
		tips
Maximum input frequency	signal with minimum input voltage swing	400 MHz (meas.)
	and hysteresis setting: normal	
Maximum input voltage		±40 V (V _p)
Minimum input voltage swing		500 mV (V _{pp}) (meas.)
Threshold groups		D0 to D3, D4 to D7, D8 to D11 and D12 to
		D15
Threshold level	range	±8 V in 25 mV steps
	predefined	CMOS 5.0 V, CMOS 3.3 V, CMOS 2.5 V,
		TTL, ECL, PECL, LVPECL
Threshold accuracy		±(100 mV + 3 % of threshold setting)
Comparator hysteresis		normal, robust, maximum

Horizontal system

Channel deskew	range for each channel	±200 ns
Channel-to-channel skew		< 500 ps (meas.)

Acquisition system

Sampling rate	max.	5 Gsample/s on each channel
Realtime waveform acquisition rate	max.	> 200 000 waveforms/s
Memory depth	at max. sampling rates	200 Msample for every channel
	at lower sampling rates	100 Msample for every channel
Decimation		pulses lost due to decimation are
		displayed

Trigger system

Holdoff range	time	100 ns to 10 s, fixed and random	
	events	1 event to 2 000 000 000 events	

Trigger modes				
Edge	triggers on specified slope (po	triggers on specified slope (positive, negative or either) in the source signal		
	sources	any channel from D0 to D15 or any logical combination of D0 to D15		
Width	triggers on positive or negative be shorter, longer, equal, insid	e pulse of specified width in the source signal; width can le or outside the interval		
	sources	any channel from D0 to D15 or any logical combination of D0 to D15		
	pulse width	200 ps to 10 s		
Timeout	triggers when the source signatime	triggers when the source signal stays high, low or unchanged for a specified period of time		
	sources	any channel from D0 to D15 or any logical combination of D0 to D15		
	timeout	200 ps to 10 s		
Data2clock		d time violations between a clock signal and a data with a max. width of 200 ns and a position of k edge		
	data signal	any subset of channels from D0 to D15 or any user-defined bus signal		
	clock signal	any channel from D0 to D15		

Pattern		triggers when the source goes true or stays true for a period of time shorter, longer, equal, inside or outside a specified range	
	sources	any logical combination of D0 to D15 or any user-defined bus signal	
	pulse width	200 ps to 10 s	
State	triggers on the slope (positive, matches a user-defined logical	negative or either) of the clock signal when data signal state	
	data signal	any logical combination of D0 to D15 or any user-defined bus signal	
	clock signal	any channel from D0 to D15	
Serial pattern		triggers on a serial data pattern of up to 32 bit; pattern bits may be high (H), low (L) or don't care (X); clock edge slope may be positive, negative or either	
	data signal	any channel from D0 to D15 or any logical combination of D15 to D15	
	clock signal	any channel from D0 to D15	
	max. data rate	1 Gbps	
Serial bus trigger	basic	I ² C, SPI, UART/RS-232	
	optional	LIN, CAN, FlexRay™ and I2S with	
	-	dedicated software options	
	sources	any channel from D0 to D15	

Waveform measurements

General features	measurement panels, gate, statistics,
	long-term analysis and limit check; see
	features of the base unit
Measurement sources	all channels from D0 to D15 or any logical
	combination of D0 to D15
Automatic measurements	positive pulse width, negative pulse width,
	period, frequency, burst width, delay,
	phase, positive duty cycle, negative duty
	cycle, positive pulse count, negative pulse
	count, rising edge count, falling edge
	count
Additional cursor function	display of decoded bus value at the cursor
	position

Waveform math

Function	any logical combination of D0 to D15

Search and mark functions

The search function will be available in a future software release.

Display characteristics

Display of logical channels		selectable size and position on screen, diagram configuration by dragging and dropping signal icons
Bus decode	number of bus signals	4
	bus types	unclocked and clocked
	display types	decoded bus, logical signal, bus + logical signal, amplitude signal, amplitude + logical signal, tabulated list (decoded time interval selected with cursors)
	position and size	size and position on screen selectable
	data format of decoded bus	hex, unsigned integer, signed integer, fractional, binary
	data format of amplitude signal	unsigned integer, signed integer, fractional, binary offset
Channel activity display		independent of the scope acquisition, the state (stays low, stays high or toggles) of the channels from D0 to D15 is displayed in the signal icon

R&S®RTO-B4

OCXO, precision reference frequency with reference input and output connectors		
Timebase accuracy	OCXO	see "Horizontal system"
Reference output	connector	BNC female
	impedance	50 Ω (nom.)
	output frequency with OCXO	10 MHz (nom.)
	output frequency with auxiliary reference	same as auxiliary reference
	level	> 7 dBm
Auxiliary reference input	connector	BNC female
	impedance	50 Ω (nom.)
	input frequency range	1 MHz ≤ f _{in} ≤ 20 MHz, in 1 MHz steps
	required level	≥ 0 dBm into 50 Ω

R&S®RTO-B10

Additional GPIB interface	
Function	interface in line with IEC 625-2
	(IEEE 488.2)
Command set	SCPI 1999.0
Connector	24-pin Amphenol female
Interface functions	SH1, AH1, T6, L4, SR1, RL1, PP1, DC1,
	DT1, C0

R&S®RTO-B18

Solid state disk	
Disk type	solid state disk
Disk size	≥ 240 Gbyte (nom.)
Firmware	Is installed upon delivery. If ordered subsequently, used operating system (Windows XP embedded or Windows 7 embedded) must be specified in order and disk drive will be delivered with removable hard disk drive holder.

R&S®RTO-B19

Additional removable hard disk	
Disk type	hard disk
Disk size	≥ 500 Gbyte (nom.)
Firmware	Is installed upon delivery. If ordered
	subsequently, used operating system
	(Windows XP embedded or Windows 7
	embedded) must be specified in order.

I ² C decoding		
Protocol configuration	bit rate	up to 3.4 Mbps (auto-detected)
	auto threshold setup	assisted threshold configuration for I ² C
		triggering and decoding
	device list	associate frame address with symbolic ID
Trigger (included in standard equipment)	source (clock and data)	any input channel or logical channel
	trigger event setup	start, stop, restart, missing ACK, address,
		data, address + data
	address setup	7 bit or 10 bit address (value in hex,
		decimal, octal or binary); ACK, NACK or
		either; read, write or either; R/W bit
		included in address value or apart;
		condition =, \neq , \geq , \leq , in range, out of range
	data setup	data pattern up to 8 byte (hex, decimal,
		octal or binary); condition =, \neq ; \geq , \leq , in
		range, out of range; offset within frame in
		range from 0 byte to 4095 byte
Decode	source (clock and data)	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
		signal, tabulated list
	color coding	frame, start/restart, address, R/W bit, data
		ACK/NACK, stop, error
	address and data format	hex, decimal, octal, binary, ASCII;
		symbolic names for user-defined subset of
		addresses

SPI decoding		
Protocol configuration	type	2-wire, 3-wire and 4-wire SPI
	bit rate	auto-detected
	bit order	LSB first, MSB first
	word size	4 bit to 32 bit
	frame condition	SS, timeout
	polarity (MOSI, MISO, SS, CLK)	active high, active low
	phase (CLK)	first edge, second edge
	auto threshold setup	assisted threshold configuration for SPI triggering and decoding
Trigger (included in standard equipment)	source (MOSI, MISO, SS, CLK)	any input channel or logical channel
	bit rate	up to 50 Mbps
	trigger event setup	start of frame, MOSI, MISO, MOSI + MISO
	data setup	data pattern up to 256 bit (hex or binary); condition =, ≠; offset within frame in range from 0 bit to 32767 bit
Decode	source (MOSI, MISO, SS, CLK)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame, word, error
	data format	hex, decimal, octal, binary, ASCII

UART/RS-232/RS-422/RS-485 decoding		
Protocol configuration	bit rate	300 bps to 20 Mbps
	signal polarity	idle low, idle high
	number of bits	5 bit to 8 bit
	bit order	LSB first, MSB first
	parity	odd, even, mark, space, none
	stop bit	1, 1.5 or 2 bit periods
	end of packet	word, timeout, none
	auto threshold setup	assisted threshold configuration for
		UART triggering and decoding
Trigger (included in standard equipment)	source (TX and RX)	any input channel or logical channel
	trigger event setup	start bit, packet start, data, parity error,
		break condition
	data setup	data pattern up to 256 bit (hex, decimal,
		octal, binary or ASCII); condition =, ≠;
		offset within packet in range 0 bit to
		32767 bit
Decode	source (TX and RX)	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
		signal, tabulated list
	color coding	packet, data payload, start error, parity
		error, stop error
	data format	hex, decimal, octal, binary, ASCII

CAN triggering and decoding		
Protocol configuration	signal type	CAN_H, CAN_L
	bit rate	100 bps to 1 Mbps
	sampling point	5 % to 95 % within bit period
	device list	associate frame identifier with symbolic ID
	auto threshold setup	assisted threshold configuration for CAN
		triggering and decoding
Trigger	source	any input channel or logical channel
	trigger event setup	start of frame, frame type, identifier,
		identifier + data, error condition (any
		combination of CRC error, bit stuffing
		error, form error and ACK error)
	identifier setup	frame type (data, remote or both),
		identifier type (standard or extended);
		condition =, \neq , \geq , \leq , in range, out of range
	data setup	data pattern up to 8 byte (hex, decimal,
		octal or binary); big-endian or little-endian;
		condition =, \neq ; \geq , \leq , in range, out of range
Decode	source	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
		signal, tabulated list
	color coding	start of frame, identifier, DLC, data
		payload, CRC, end of frame, error frame,
		overload frame, CRC error, bit stuffing
		error
	data format	hex, decimal, octal, binary, ASCII
Search	source	any input channel or logical channel
	search event setup	combination of start of frame, frame type,
		identifier, identifier + data, error condition
		(any combination of CRC error, bit stuffing
		error, form error and ACK error)
	event settings	same as trigger event settings

LIN triggering and decoding		
Protocol configuration	version	1.3, 2.x or SAE J602; mixed traffic is supported
	bit rate	standard bit rate (1.2/2.4/4.8/9.6/10.417/ 19.2 kbps) or user-defined bit rate in range from 1 kbps to 20 kbps
	device list	associate frame identifier with symbolic ID, data length and protocol version
	auto threshold setup	assisted threshold configuration for LIN triggering and decoding
Trigger	source	any input channel
	trigger event setup	start of frame (sync break), identifier, identifier + data, wakeup frame, error condition (any combination of checksum error, parity error and sync field error)
	identifier setup	range from 0d to 63d; select condition =, ≠, ≥, ≤, in range, out of range for trigger "identifier"; select single identifier and condition = for trigger "identifier + data"
	data setup	data pattern up to 8 byte (hex, decimal, octal or binary); condition =, \neq , \geq , \leq , in range, out of range
Decode	source (TX and RX)	any input channel, math waveform, reference waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame, frame identifier, data payload, checksum, error condition
	data format	hex, decimal, octal, binary, ASCII

FlexRay™ triggering and deco	ding	
Protocol configuration	signal type	single-ended, differential, logic
	channel type	channel A, channel B
	bit rate	standard bit rates (2.5/5.0/10.0 Mbps)
	device list	associate frame identifier with symbolic ID
	auto threshold setup	assisted threshold configuration for
		FlexRay™ triggering and decoding
	source	any input channel or logical channel
Trigger Trigger	trigger event setup	start of frame, header + data, symbol,
		wakeup, error condition (any combination
		of FSS error, BSS error, FES error, heade
		CRC error and frame CRC error)
	header setup	indicator bits, identifier, payload length,
	· ·	cycle count
	indicator bits setup	payload preamble bit, null frame bit, sync
	·	frame bit and startup frame bit separately
		configurable (1, 0 or don't care)
	identifier setup	condition =, ≠, ≥, ≤, in range, out of range
	payload length setup	condition =, ≠, ≥, ≤, in range, out of range
	cycle count	condition =, ≠, ≥, ≤, in range, out of range;
	·	step parameter for selection of non-
		contiguous values within provided range
	data setup	data pattern up to 8 byte (hex, decimal,
	· ·	octal or binary); condition =, \neq , \geq , \leq , in
		range, out of range; offset within frame in
		range from 0 byte to 253 byte
Decode	source	any input channel, math waveform,
		reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical
	. , , , ,	signal, tabulated list
	color coding	frame, frame header, identifier, payload
		length, header CRC, cycle count, data
		payload, frame CRC, error condition
	data format	hex, decimal, octal, binary, ASCII
Search	search event setup	combination of start of frame, header +
	·	data, symbol, wakeup, error condition (any
		combination of FSS error, BSS error, FES
		error, header CRC error and frame CRC
		error)
	event settings	same as trigger event settings

Protocol configuration	signal type	I ² S standard, left justified, right justified, TDM
	auto threshold setup	assisted threshold configuration for I ² S triggering and decoding
Trigger	source	any input channel or logical channel
	trigger event setup	data, window, frame condition, word select, error condition
	data setup	data pattern of an audio channel up to 4 byte (hex, signed decimal, unsigned decimal, octal or binary); condition =, \neq ; \geq , \leq , $<$, $>$, in range, out of range
	window setup	word count of data pattern of an audio channel up to 4 byte (hex, signed decimal, unsigned decimal, octal or binary); condition =, ≠; ≥, ≤, <, >, in range, out of range
	frame condition setup	combination of audio channels in a frame, up to 4 byte (hex, signed decimal, unsigned decimal, octal or binary); condition =, \neq ; \geq , \leq , $<$, $>$, in range, out of range
	word select setup	rising or falling edge of word select input channel
	error condition setup	source of word select
Decode	source	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus and logical signal, tabulated list
	color coding	audio frame, frame error, incomplete frame
	data format	hex, unsigned decimal, signed decimal (two's complement), octal, binary, ASCII
Protocol measurements	audio display	display of audio waveform for specified audio channels
	long-term display	history of selected audio data as trace against measurements, waveforms and time index

MIL-STD-1553 triggering and de		
Protocol configuration	signal type	single-ended
	bit rate	standard bit rate (1 Mbit/s)
	polarity	normal, inverted
	device list	associate frame identifier with symbolic II
	auto threshold setup	assisted threshold configuration
	timing	min. gap (2 μs to 262 μs) or off; max. response (2 μs to 262 μs) or off
Trigger	trigger event setup	sync, word, data word, command/status word, command word, status word, error condition
	sync and word setup	all words, command/status word, data word
	data word setup	RTA (condition =, \neq , \geq , \leq , in range, out of range); data pattern (condition =, \neq , \geq , \leq , range, out of range); payload data index (=, $<$, $>$, \geq , \leq , range); max length of data pattern is 4 byte
	command/status word setup	RTA (condition =, \neq , \geq , \leq , in range, out of range); 11 bit pattern (condition =, \neq , \geq , \leq in range, out of range)
	command word setup	RTA (condition =, \neq , \geq , \leq , in range, out of range); subaddress/mode (condition =, \neq , \geq , \leq , in range, out of range); data word count/mode count (condition =, \neq , \geq , \leq , in range, out of range); direction (T/R)
	status word	RTA (condition =, ≠, ≥, ≤, in range, out of range); status flags (message error, instrumentation, service request, broadcast command, busy, subsystem flag, dynamic bus control, terminal flag)
	error condition	any combination of sync error, Mancheste error, parity error, timing error (see protocol configuration)
Decode	source	any analog input channel, math waveform reference waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame (word), sync, RTA, status bit field, parity, data field, error condition
	data format	hex, octal, binary, ASCII, signed, unsigne
Search	search event setup	sync, word, data word, command/status word, command word, status word, error condition
	event settings	same as trigger event settings

ARINC 429 triggering and deco	ding	
Protocol configuration	signal type	single-ended
	bit rate	high (100 kbit/s)
		low (12 kbit/s to 14.5 kbit/s)
	polarity	A leg, B leg
	device list	associate frame identifier with symbolic ID
	auto threshold setup	assisted threshold configuration
	timing	min. gap (0 bit to 100 bits) or off; max. gap (0 bit to 1000 bits) or off
Trigger	trigger event setup	word start, word stop, label + data, error condition
	label + data setup	label (condition =, \neq , \geq , \leq , in range, out of range); data (condition =, \neq , \geq , \leq , in range, out of range); SDI/SSM
	error condition	any combination of coding error, parity error, timing error (see protocol configuration)
Decode	source	any analog input channel, math waveform, reference waveform
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame (word), label, SDI, data, SSM, parity, error condition
	data format	hex, octal, binary, ASCII, signed, unsigned
Search	search event setup	word start, word stop, label + data, error condition
	event settings	same as trigger event settings

CAN FD triggering and decoding	ng			
Protocol configuration	signal type	CAN_H, CAN_L		
	bit rate	bit rate		
	arbitration rate	10 kbps to 1 Mbps		
	data rate	10 kbps to 15 Mbps		
	sampling point	5 % to 95 % within bit period		
	device list	associate frame identifier with symbolic ID		
	auto threshold setup	assisted threshold configuration		
Trigger	source	any input channel or logical channel		
	trigger event setup	start of frame, frame type, identifier,		
		identifier + data, error condition (any		
		combination of CRC error, bit stuffing		
		error, form error and ACK error)		
	identifier setup	frame type (data, remote or both),		
		identifier type (standard or extended);		
		condition =, \neq , \geq , \leq , in range, out of range		
	FD bits	FDF and ESI (0, 1, X), BRS (0,1)		
	data setup	data pattern up to 8 bytes in the complete		
		data range (hex, decimal, octal or binary);		
		condition =, \neq ; \geq , \leq , in range, out of range		
Decode	source	any input channel, math waveform,		
		reference waveform, logical channel		
	display type	decoded bus, logical signal, bus + logical		
		signal, tabulated list		
	color coding	start of frame, identifier, FD bits, DLC,		
		data payload, CRC, end of frame, error		
		frame, overload frame, CRC error, bit		
		stuffing error		
	data format	hex, decimal, octal, binary, ASCII		
Search	source	any input channel or logical channel		
	search event setup	combination of start of frame, frame type,		
		identifier, identifier + data, error condition		
		(any combination of CRC error, bit stuffing		
		error, form error and ACK error)		
	event settings	same as trigger event settings		

I/Q software interface					
General	function		mixing, filtering, decimation and recording of RF or baseband signals as I/Q samples		
	input signals (2 channel models)		two real RF signals or		
		,	one complex I/Q signa	I	
	input signals (4 channe	l models)	four real RF signals or		
	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	,	two complex I/Q signals or		
			two real RF signals and		
			one complex I/Q signal		
	mixer frequency			GHz (or mixer deactivated	
	sampling rate of record	ed I/O samples	between 1 ksample/s a		
	digital filter bandwidth	ou ii Q cumpioc		4 % to 80 % of sampling rate	
	(flat frequency response	۵)			
	sampling rate of record		between 1 ksample/s a selectable	between 1 ksample/s and 10 Gsample/s user-	
	recording length			one or two input signals;	
	recording length				
				hree or four input signals;	
- ·				endent of sampling rate	
Trigger	mode		auto or normal		
	operation			gnal after A/D conversion	
			serial bus and MSO tri		
	additional modes		NFC-A, 106 kbps, SEN		
			NFC-B, 106 kbps, SEN		
				04 kbps, start of sequence	
			(SoS) length: 48 bit or		
Display			magnitude of the dowr	•	
Amplitude flatness with RF signal input (meas.)	R&S®RTO1002 and R&S®RTO1004	max. used center frequency	with I/Q bandwidth 100 MHz	with I/Q bandwidth 250 MHz	
		≤ 100 MHz	±0.10 dB		
		≤ 200 MHz	±0.12 dB	±0.30 dB	
		≤ 300 MHz	±0.20 dB	±0.50 dB	
		≤ 400 MHz	±0.25 dB	±0.70 dB	
		≤ 500 MHz	±0.35 dB	±1.00 dB	
	R&S®RTO1012 and	max. used center	with I/Q bandwidth	with I/Q bandwidth	
	R&S®RTO1014	frequency	100 MHz	250 MHz	
	1100 1110 1011	≤ 100 MHz	±0.10 dB		
		≤ 200 MHz	±0.10 dB	±0.15 dB	
		≤ 500 MHz	±0.10 dB	±0.25 dB	
		≤ 750 MHz	±0.15 dB	±0.40 dB	
		≤ 1 GHz	±0.30 dB	±0.90 dB	
	R&S®RTO1022 and	max. used center	with I/Q bandwidth	with I/Q bandwidth	
	R&S®RTO1024		100 MHz	500 MHz	
	K&3 K101024	frequency ≤ 100 MHz	±0.10 dB	300 WH 12	
				10.10 dD	
		≤ 500 MHz	±0.10 dB	±0.10 dB	
		≤ 1 GHz	±0.17 dB	±0.35 dB	
		≤ 1.5 GHz	±0.20 dB	±0.50 dB	
	DAG®DTO 1211	≤ 2 GHz	±0.35 dB	±1.00 dB	
	R&S®RTO1044	max. used center	with I/Q bandwidth	with I/Q bandwidth	
		frequency	100 MHz	500 MHz	
		≤ 100 MHz	±0.10 dB		
		≤ 500 MHz	±0.10 dB	±0.10 dB	
		≤ 1 GHz	±0.10 dB	±0.10 dB	
		≤ 2 GHz	±0.10 dB	±0.15 dB	
		≤ 3 GHz	±0.12 dB	±0.30 dB	
		≤ 4 GHz	±0.30 dB	±0.75 dB	

Basic jitter analysis	TI DAG@DTG 1/40 ''''		
General description	The R&S®RTO-K12 jitter analysis option extends the functionality of the standard R&S®RTO firmware with a suite of measurement, analysis and visualization tools for		
	signal integrity analysis and jitter ch		
Waveform measurements	category	jitter	
	measurement functions	cycle-to-cycle jitter, N-cycle jitter, cycle-to-cycle width, cycle-to-cycle duty cycle, time-interval error, data rate, unit interval, skew delay, skew phase; the standard time measurements period, frequency and setup/hold are also available in the jitter category for convenience	
	track	measurement results displayed as continuous trace that is time-correlated to the measurement source; applicable to time measurements from categories "jitter"	
		and "amplitude and time"; track trace may be used as source for cursor measurements, automatic measurements, math waveforms and reference waveforms	
Waveform math	FFT on track	FFT spectrum of the track trace of measurement results	
	CDR transform	recovers clock timing from source waveform with software CDR and generates synthetic clock waveform that is time-correlated to source	
Software clock data recovery (CDR)	number of CDR instances	up to 2; independently configurable	
20a. 2 0.00 aa.a 100010.) (0211)	algorithm	phase-locked loop (PLL)	
	configuration	nominal bit rate, PLL order (first or second), loop bandwidth, damping factor, initial phase alignment, result selection during initial synchronization	
Jitter Wizard	The Jitter Wizard assists the user in the step-by-step configuration of the R&S®RTO digital oscilloscope for the measurements period/frequency, cycle-by-cycle jitter, time interval error (TIE) and skew.		
Mask testing with eye mask assistant	primary mask shape		
	type	diamond, square, hexagon, octagon	
	dimensions	main and secondary height, main and secondary width, depending on selected shape	
	position	vertical offset, horizontal offset	
	secondary mask shapes	TOTALOGI CITOGO, MONEGOTIAN OTTOGO	
	locations	any combination of left, right, top, bottom	
	position	horizontal and vertical offset with respect	
	ροσιαστι	to center of primary mask shape	

Realtime clock data recovery (CDR) General description	The R&S®RTO-K13 realtime clock data	recovery ontion activates the hardware CDR	
General description	The R&S®RTO-K13 realtime clock data recovery option activates the hardware CDR circuitry integrated into the R&S®RTO digital oscilloscope. It provides realtime clock		
		erial data up to 5.0 Gbps. The recovered clock	
	may be used for triggering and jitter anal		
Hardware clock data recovery (CDR)	description	fully digital implementation of PLL-based	
natuwale clock data recovery (CDR)	description	clock data recovery	
	sources		
	R&S [®] RTO1002, R&S [®] RTO1012, R&S [®] RTO1022	channel 1, channel 2	
	R&S®RTO1004, R&S®RTO1014,	channel 1, channel 2, channel 3,	
	R&S®RTO1024, R&S®RTO1044	channel 4	
	configuration parameters	PLL order (first or second), nominal bit	
		rate, loop bandwidth, relative bandwidth,	
		damping factor, unit interval offset	
	bit rate range		
	R&S®RTO1002, R&S®RTO1004,	200 kbps to 2.5 Gbps	
	R&S®RTO1012, R&S®RTO1014,	·	
	R&S®RTO1022, R&S®RTO1024		
	R&S®RTO1044	200 kbps to 2.5 Gpbs standard,	
		400 kbps to 5.0 Gbps when operating at	
		20 Gsample/s realtime sampling rate 4	
	relative bandwidth	1/500 to 1/3000 of the nominal bit rate	
	damping factor	0.5 to 1.0; relevant for 2 nd order PLL only	
	unit interval offset	0.0 to 1.0	
Trigger modes	CDR	triggers on clock signal recovered from the	
		trigger source signal; phase of the trigger	
		instant user-selectable as fraction of bit	
		period	
	serial pattern	main trigger mode "serial pattern" supports	
	·	the hardware CDR as additional clock	
		source; sampling point user-selectable as	
		fraction of bit period	

⁴ The R&S®RTO1044 frontend samples at 20 Gsample/s when: at most one channel from each pair {channel1, channel2} and {channel3, channel4} is active; and the user-selected sampling resolution in realtime sampling mode or interpolated time sampling mode is 50 ps or smaller.

High definition mode			
General description	waveform signal by using digita	The R&S®RTO-K17 high definition mode increases the numeric resolution of the waveform signal by using digital filtering, leading to a reduced noise. Because of the R&S®RTO digital trigger concept the signals with increased numeric resolution are used as input for triggering.	
Numeric resolution	bandwidth	bit resolution	
	10 kHz to 50 MHz	16 bit	
	100 MHz	14 bit	
	200 MHz	13 bit	
	300 MHz	12 bit	
	500 MHz	12 bit	
	1 GHz	10 bit	
Realtime sampling rate		max. 5 Gsample/s on each channel	
Input sensitivity		Input sensitivity range is extended down to 500 μ V/div; 500 μ V/div is a magnification of the 1 mV/div setting.	

The R&S®RTO-K21 option is available for R&S®RTO models 1316.1000K24, 1316.1000K44 and 1304.6002K24 only. The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTO-K21 makes it possible to perform USB 2.0 compliance test measurements with R&S®ScopeSuite, including tests for USB 2.0 (high speed), USB 1.1 (full speed) and USB 1.0 (low speed) with the R&S®RTO. R&S®ScopeSuite supports the R&S®RT-ZF1 USB 2.0 compliance test fixture set and the Allion USB test fixture solutions and the USB-IF signal quality board device/host; it requires Windows 7.

Supported USB compliance	tests	
USB device test	high speed	signal quality (EL_2,4,5,6,7); packet parameters (EL_21,22,25); chirp timing (EL_28,29,31); suspend/resume/reset timing (EL_27,28,38,39,40); test J/K, SE0_NAK (EL_8,9); receiver sensitivity (EL_16,17,18)
	full speed and low speed	full speed signal quality; back voltage; inrush current
USB host test	high speed	signal quality (EL_2,3,6,7); packet parameters (EL_21,22,23,25,55); chirp timing (EL_33,34,35); suspend/resume/reset timing (EL_39,41); test J/K, SE0_NAK (EL_8,9)
	full speed and low speed	low speed signal quality downstream; full speed signal quality downstream; drop; droop
USB hub test	high speed	signal quality upstream (EL_2,46,6,7); signal quality downstream (EL_2,3,6,7); jitter downstream (EL_47); packet parameters upstream (EL_21,22,25); hub receiver sensitivity upstream (EL_16,17,18); repeater downstream (EL_42,43,44,45,48); repeater upstream (EL_42,43,44,45); chirp timing upstream (EL_28,29,31); suspend/resume/reset timing upstream (EL_27,28,38,39,40); tes J/K, SE0_NAK upstream (EL_8,9); test J/K, SE0_NAK downstream (EL_8,9)
	full speed and low speed	low speed signal quality downstream; full speed signal quality upstream; full speed signal quality downstream; inrush current upstream; drop downstream; droop
		downstream; back voltage

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTO-K22 makes it possible to perform Ethernet compliance test measurements with R&S®ScopeSuite, including tests for 10BaseT, 100BaseTx and 1000BaseT with the R&S®RTO. R&S®ScopeSuite supports the R&S®RT-ZF2 Ethernet compliance test fixture set; it requires Windows 7.

Supported Ethernet comp 1000BaseT	with/without disturber	with/without TX CLK transmitter
TotobaseT	with without disturber	distortion (40.6.1.2.4)
		peak differential output voltage
		(40.6.1.2.1)
		maximum output droop (40.6.1.2.2)
		differential output templates (40.6.1.2.3)
	with TX CLK	jitter master mode (40.6.1.2.5)
		jitter slave mode (40.6.1.2.5)
	without TX CLK	jitter master mode (40.6.1.2.5)
	common	MDI return loss (40.8.3.1); common-
		mode output voltage (40.8.3.3)
100BaseTx		amplitude domain tests
		(9.1.2.2, 9.1.3 and 9.1.4)
		rise and fall times (9.1.6)
		peak to peak duty cycle distortion (9.1.8)
		peak to peak transmitter jitter (9.1.9)
		active output interface template (annex J
		transmitter return loss (9.1.5)
		receiver return loss (9.2.2)
10BaseT	no TPM	link test pulse template (14.3.1.2.1)
		TP_IDL template (14.3.1.2.1)
		peak differential voltage (14.3.1.2.1)
		harmonic content (14.3.1.2.1)
		output timing jitter (14.3.1.2.3)
	with TPM	link test pulse template (14.3.1.2.1)
		TP_IDL template (14.3.1.2.1)
		MAU template (14.3.1.2.1)
		output timing jitter (14.3.1.2.3)
	common	transmitter return loss (14.3.1.2.2);
		receiver return loss (14.3.1.3.4)
		common-mode output voltage
		(14.3.1.2.5)

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTO-K23 makes it possible to perform Ethernet compliance test measurements with R&S®ScopeSuite, including tests for 10GBaseT with the R&S®RTO.

R&S®ScopeSuite supports the R&S®RT-ZF2 Ethernet compliance test fixture set; it requires Windows 7.

Supported Ethernet compliance tests	
10GBaseT	maximum output droop (55.5.3.1)
	transmitter linearity (55.5.3.2)
	transmitter timing jitter master mode (55.5.3.3)
	transmitter timing jitter slave mode
	(55.5.3.3)
	transmitter power spectral density
	(55.5.3.4)
	transmitter power level (55.5.3.4)
	transmitter clock frequency (55.5.3.5)
	MDI return loss (55.8.2.1)

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTO-K24 makes it possible to perform BroadR-Reach compliance test measurements with R&S®ScopeSuite.

R&S®ScopeSuite supports the R&S®RT-ZF2 Ethernet compliance test fixture set; it requires Windows 7.

Supported BroadR-Reach compliance tests		
BroadR-Reach	transmitter output droop (5.4.1)	
	transmitter distortion with and without	
	disturber (5.4.2)	
	transmitter timing jitter master mode	
	(5.4.3)	
	transmitter timing jitter slave mode (5.4.3)	
	transmitter tower spectral density (5.4.4)	
	transmitter clock frequency (5.4.5)	
	MDI return loss (8.2.2)	

The option is used in combination with the free-of-charge R&S®ScopeSuite PC software, which can be downloaded from the Rohde & Schwarz website. R&S®RTO-K26 makes it possible to perform D-PHY compliance test measurements with R&S®ScopeSuite. R&S®ScopeSuite requires Windows 7.

pop 1 (7 tests): data lane LP-TX signaling requirements 1.1.1 data lane LP-TX Thevenin output high level voltage (V _{co.}) 1.1.2 data lane LP-TX Thevenin output low level voltage (V _{co.}) 1.1.3 data lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.1.4 data lane LP-TX from 85 % to 1.5 % fall time (T _{co.}) 1.1.5 data lane LP-TX pulse width of exclusive-OR clock (T _{co.Puser TX}) 1.1.6 data lane LP-TX pulse width of exclusive-OR clock (T _{co.Puser TX}) 1.1.7- data lane LP-TX promote exclusive-OR clock (T _{co.Puser TX}) 1.1.7- data lane LP-TX promote for exclusive-OR clock (T _{co.Puser TX}) 1.1.7- data lane LP-TX promote exclusive-OR clock (T _{co.Puser TX}) 1.1.7- data lane LP-TX promote exclusive-OR clock (T _{co.Puser TX}) 1.1.7- data lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.2- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.3- data lane HS-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.4- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.5- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.5- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.2.5- clock lane LP-TX from 15 % to 85 % rise time (T _{co.}) 1.3.5- data lane HS-TX dynamic common-level variations above 450 MHz 2 Moranza 1.3.1- data lane HS-TX dynamic common-level variations above 450 MHz 2 Moranza 1.3.1- data lane HS-TX from 30 % to 80 % rise time f _{co.} 1.3.1- data lane HS-TX from 30 % to 80 % rise time f _{co.} 1.3.1- data lane HS-TX from 30 % to 80 % rise time f _{co.} 1.3.1- data lane HS-TX from 30 % to 80 % rise time f _{co.} 1.3.1- data lane HS-TX from 30 % to 80 % rise time f _{co.} 1.3.1-	Supported D-PHY compliance tests		
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low level voltage (V _m) 1.1.3 – data lane LP-TX from 15 % to 85 % rise time (T _{mp}) 1.1.4 – data lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.1.5 – data lane LP-TX siew rate versus (C _{LORG} (GWOte _m) 1.1.6 – data lane LP-TX siew rate versus (C _{LORG} (GWOte _m) 1.1.6 – data lane LP-TX pulse width of exclusive-OR clock (T _{LP-MB-K-T}) 1.1.7 – data lane LP-TX pulse width of exclusive-OR clock (T _{LP-MB-K-T}) 1.1.7 – data lane LP-TX prevenin output high level voltage (V _{GL}) 1.2.2 – clock lane LP-TX Thevenin output low level voltage (V _{GL}) 1.2.3 – clock lane LP-TX from 15 % to 85 % rise time (T _{mp}) 1.2.4 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.2.5 – clock lane LP-TX from 85 % to 15 % fall time (T _{mp}) 1.3.5 – data lane HS entry data lane T _{mp} , represent the second value of the second value (T _{mp}) 1.3.5 – data lane HS entry data lane T _{mp} , represent the second value (T _{mp}) 1.3.5 – data lane HS-TX differential voltages (T _{mp}) and V _{mp} , represented (T _{mp}) 1.3.5 – data lane HS-TX differential voltages (T _{mp}) and V _{mp} , represented (T _{mp}) 1.3.5 – data lane HS-TX dynamic common-level variations above 450 MHz AV _{cmm} , 1.3.1 – data lane HS-TX from 80 % to 80 % rise time t _m 1.3.1 – data lane HS-TX from 80 % to 80 % rise time t _{mp} 1.3.1 – data lane HS-TX from 80 % to 80 % rise time t _{mp} 1.3.1 – data lane HS-TX from 80 % to 80 % rise time t _{mp} 1.3.1 – data lane HS-TX from 80 % to 80 % rise time t _{mp} 1.3.1 – data lane HS-TX from 80 % to 80 % rise time			1.1.2 – data lane LP-TX Thevenin output
1.1.3 – data lane LP-TX from 15 % to 85 % rise time (T _{ERP}) 1.1.4 – data lane LP-TX siew rate versus C _{LOGO} (GV/0f _{ERP}) 1.1.5 – data lane LP-TX siew rate versus C _{LOGO} (GV/0f _{ERP}) 1.1.6 – data lane LP-TX pulse width of exclusive-OR clock (T _{ERP}) exclusive-OR clock (T _{ERP}) 1.1.7 – data lane LP-TX period of exclusive-OR clock (T _{ERP}) exclusive-OR clock (I _E			•
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T _{HS-PREPARE} Value 1.3.3 − data lane HS entry: data lane T _{HS-PREPARE} + T _{HS-ZERO} value 1.3.4 − data lane HS-TX differential voltages V _{OD(0)} and V _{OD(1)} 1.3.5 − data lane HS-TX differential voltage mismatch ΔV _{OD} 1.3.6 − data lane HS-TX single-ended output voltages V _{OHHS(DP)} and V _{OHHS(DN)} 1.3.7 − data lane HS-TX static common- mode voltages V _{OHHS(DP)} and V _{OMTX(D)} 1.3.8 − data lane HS-TX static common- mode voltages mismatch ΔV _{CMTX(1)} 1.3.9 − data lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz ΔV _{CMTX(EF)} 1.3.10 − data lane HS-TX dynamic common-level variations above 450 MHz ΔV _{CMTX(HF)} 1.3.11 − data lane HS-TX from 20 % to 80 % rise time t _R 1.3.12 − data lane HS-TX from 80 % to 20 % fall time t _E 1.3.13 − data lane HS exit: T _{HS-TRAIL} value 1.3.14 − data lane HS exit: T _{HS-TRAIL} value 1.3.15 − data lane HS exit: T _{EGT} value			-
1.3.3 – data lane HS entry: data lane This-prepare + This-zero value 1.3.4 – data lane HS-TX differential voltages V _{OD(0)} and V _{OD(1)} 1.3.5 – data lane HS-TX differential voltage mismatch ΔV _{OD} 1.3.6 – data lane HS-TX single-ended output voltages V _{OHHS(OP)} and V _{OHHS(ON)} 1.3.7 – data lane HS-TX static commonmode voltages V _{OMTX(1)} and V _{OHTX(0)} 1.3.8 – data lane HS-TX static commonmode voltage mismatch ΔV _{CMTX(1)} 1.3.9 – data lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz ΔV _{CMTX(EF)} 1.3.10 – data lane HS-TX dynamic common-level variations above 450 MHz ΔV _{CMTX(EF)} 1.3.11 – data lane HS-TX from 20 % to 80 % rise time t _R 1.3.12 – data lane HS-TX from 80 % to 20 % fall time t _F 1.3.13 – data lane HS exit: T _{HS-TRAIL} value 1.3.14 – data lane HS exit: This time Trect 1.3.15 – data lane HS exit: Trect value			1.3.2 – data lane HS entry: data lane
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$\begin{array}{c} 1.3.4-\text{data lane HS-TX differential} \\ \text{voltages } V_{\text{OD(0)}} \text{ and } V_{\text{OD(1)}} \\ 1.3.5-\text{data lane HS-TX differential} \\ \text{voltage mismatch } \Delta V_{\text{OD}} \\ 1.3.6-\text{data lane HS-TX single-ended} \\ \text{output voltages } V_{\text{OHHS(DP)}} \text{ and } V_{\text{OHHS(DN)}} \\ 1.3.7-\text{data lane HS-TX static common-mode voltages } V_{\text{CMTX(1)}} \text{ and } V_{\text{CMTX(1)}} \\ 1.3.8-\text{data lane HS-TX static common-mode voltage mismatch } \Delta V_{\text{CMTX(1,0)}} \\ 1.3.9-\text{data lane HS-TX dynamic common-level variations from 50 MHz to } 450 \text{ MHz } \Delta V_{\text{CMTX(1,1)}} \\ 1.3.10-\text{data lane HS-TX dynamic common-level variations above 450 MHz } \Delta V_{\text{CMTX(HF)}} \\ 1.3.11-\text{data lane HS-TX from 20 \% to } 80 \text{ % rise time t}_{R} \\ 1.3.12-\text{data lane HS-TX from 80 \% to } 20 \text{ % fall time t}_{F} \\ 1.3.13-\text{data lane HS exit: T}_{\text{HS-TRAIL}} \text{ value} \\ 1.3.14-\text{data lane HS exit: T}_{\text{HS-TRAIL}} \text{ value} \\ 1.3.14-\text{data lane HS exit: T}_{\text{FCOT}} \text{ value} \\ 1.3.15-\text{data lane HS exit: T}_{\text{EOT}} \text{ value} \\ \end{array}$			1.3.3 – data lane HS entry: data lane
$voltages V_{OD(0)} and V_{OD(1)} \\ 1.3.5 - data lane HS-TX differential \\ voltage mismatch \Delta V_{OD} \\ 1.3.6 - data lane HS-TX single-ended \\ output voltages V_{OHHS(DP)} and V_{OHHS(DN)} \\ 1.3.7 - data lane HS-TX static common-mode voltages V_{CMTX(1)} and V_{CMTX(0)} \\ 1.3.8 - data lane HS-TX static common-mode voltage mismatch \Delta V_{CMTX(1,0)} \\ 1.3.9 - data lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz \Delta V_{CMTX(LF)} \\ 1.3.10 - data lane HS-TX dynamic common-level variations above 450 MHz \Delta V_{CMTX(HF)} \\ 1.3.11 - data lane HS-TX from 20 \% to 80 \% rise time t_R \\ 1.3.12 - data lane HS-TX from 80 \% to 20 \% fall time t_F \\ 1.3.13 - data lane HS exit: T_{HS-TRAIL} value 1.3.14 - data lane HS exit: T_{EOT} on 30 \% to 85 \% post-EOT rise time T_{REOT} \\ 1.3.15 - data lane HS exit: T_{EOT} value $			T _{HS-PREPARE} + T _{HS-ZERO} value
$\begin{array}{c} 1.3.5 - \text{data lane HS-TX differential} \\ \text{voltage mismatch } \Delta V_{\text{OD}} \\ 1.3.6 - \text{data lane HS-TX single-ended} \\ \text{output voltages } V_{\text{OHMS(DP)}} \text{ and } V_{\text{OHMS(DN)}} \\ 1.3.7 - \text{data lane HS-TX static commonmode voltages } V_{\text{CMTX(1)}} \text{ and } V_{\text{CMTX(0)}} \\ 1.3.8 - \text{data lane HS-TX static commonmode voltage mismatch } \Delta V_{\text{CMTX(1,0)}} \\ 1.3.9 - \text{data lane HS-TX dynamic common-level variations from 50 MHz to} \\ 450 \text{ MHz } \Delta V_{\text{CMTX(LF)}} \\ 1.3.10 - \text{data lane HS-TX dynamic common-level variations above 450 MHz} \\ \Delta V_{\text{CMTX(HF)}} \\ 1.3.11 - \text{data lane HS-TX from 20 \% to} \\ 80 \text{ \% rise time } t_{\text{R}} \\ 1.3.12 - \text{data lane HS-TX from 80 \% to} \\ 20 \text{ \% fall time } t_{\text{F}} \\ 1.3.13 - \text{data lane HS exit: } T_{\text{HS-TRAIL}} \text{ value} \\ 1.3.14 - \text{data lane HS exit: from 30 \% to} \\ 85 \text{ \% post-EoT rise time } T_{\text{REOT}} \\ 1.3.15 - \text{data lane HS exit: } T_{\text{EDT}} \text{ value} \\ \end{array}$			1.3.4 – data lane HS-TX differential
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1.3.7 – data lane HS-TX static commonmode voltages V _{CMTX(1)} and V _{CMTX(0)} 1.3.8 – data lane HS-TX static commonmode voltage mismatch ΔV _{CMTX(1.0)} 1.3.9 – data lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz ΔV _{CMTX(LF)} 1.3.10 – data lane HS-TX dynamic common-level variations above 450 MHz ΔV _{CMTX(LF)} 1.3.11 – data lane HS-TX from 20 % to 80 % rise time t _R 1.3.12 – data lane HS-TX from 80 % to 20 % fall time t _F 1.3.13 – data lane HS exit: T _{HS-TRAIL} value 1.3.14 – data lane HS exit: from 30 % to 85 % post-EoT rise time T _{REOT} 1.3.15 – data lane HS exit: T _{EOT} value			1.3.6 – data lane HS-TX single-ended
1.3.7 – data lane HS-TX static commonmode voltages V _{CMTX(1)} and V _{CMTX(0)} 1.3.8 – data lane HS-TX static commonmode voltage mismatch ΔV _{CMTX(1.0)} 1.3.9 – data lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz ΔV _{CMTX(LF)} 1.3.10 – data lane HS-TX dynamic common-level variations above 450 MHz ΔV _{CMTX(LF)} 1.3.11 – data lane HS-TX from 20 % to 80 % rise time t _R 1.3.12 – data lane HS-TX from 80 % to 20 % fall time t _F 1.3.13 – data lane HS exit: T _{HS-TRAIL} value 1.3.14 – data lane HS exit: from 30 % to 85 % post-EoT rise time T _{REOT} 1.3.15 – data lane HS exit: T _{EOT} value			output voltages V _{OHHS(DP)} and V _{OHHS(DN)}
mode voltages $V_{\text{CMTX}(1)}$ and $V_{\text{CMTX}(0)}$ 1.3.8 – data lane HS-TX static commonmode voltage mismatch $\Delta V_{\text{CMTX}(1.0)}$ 1.3.9 – data lane HS-TX dynamic common-level variations from 50 MHz to 450 MHz $\Delta V_{\text{CMTX}(LF)}$ 1.3.10 – data lane HS-TX dynamic common-level variations above 450 MHz $\Delta V_{\text{CMTX}(HF)}$ 1.3.11 – data lane HS-TX from 20 % to 80 % rise time t_{R} 1.3.12 – data lane HS-TX from 80 % to 20 % fall time t_{F} 1.3.13 – data lane HS exit: $T_{\text{HS-TRAIL}}$ value 1.3.14 – data lane HS exit: from 30 % to 85 % post-EoT rise time T_{REOT} 1.3.15 – data lane HS exit: T_{EoT} value			
$1.3.8 - \text{data lane HS-TX static common-mode voltage mismatch } \Delta V_{\text{CMTX}(1.0)}$ $1.3.9 - \text{data lane HS-TX dynamic common-level variations from 50 MHz to}$ $450 \text{ MHz } \Delta V_{\text{CMTX}(LF)}$ $1.3.10 - \text{data lane HS-TX dynamic common-level variations above 450 MHz}$ $\Delta V_{\text{CMTX}(HF)}$ $1.3.11 - \text{data lane HS-TX from 20 \% to}$ $80 \% \text{ rise time t}_{R}$ $1.3.12 - \text{data lane HS-TX from 80 \% to}$ $20 \% \text{ fall time t}_{F}$ $1.3.13 - \text{data lane HS exit: } T_{\text{HS-TRAIL}} \text{ value}$ $1.3.14 - \text{data lane HS exit: from 30 \% to}$ $85 \% \text{ post-EoT rise time } T_{\text{REOT}}$ $1.3.15 - \text{data lane HS exit: } T_{\text{EOT}} \text{ value}$			
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$\begin{array}{c} 1.3.10 - \text{data lane HS-TX dynamic} \\ \text{common-level variations above 450 MHz} \\ \underline{\Delta V_{\text{CMTX(HF)}}} \\ 1.3.11 - \text{data lane HS-TX from 20 \% to} \\ 80 \% \text{ rise time } t_{\text{R}} \\ 1.3.12 - \text{data lane HS-TX from 80 \% to} \\ 20 \% \text{ fall time } t_{\text{F}} \\ 1.3.13 - \text{data lane HS exit: } T_{\text{HS-TRAIL}} \text{ value} \\ 1.3.14 - \text{data lane HS exit: from 30 \% to} \\ 85 \% \text{ post-EoT rise time } T_{\text{REOT}} \\ 1.3.15 - \text{data lane HS exit: } T_{\text{EOT}} \text{ value} \\ \end{array}$			common-level variations from 50 MHz to
common-level variations above 450 MHz $\Delta V_{\text{CMTX(HF)}}$ 1.3.11 – data lane HS-TX from 20 % to 80 % rise time t_R 1.3.12 – data lane HS-TX from 80 % to 20 % fall time t_F 1.3.13 – data lane HS exit: $T_{\text{HS-TRAIL}}$ value 1.3.14 – data lane HS exit: from 30 % to 85 % post-EoT rise time T_{REOT} 1.3.15 – data lane HS exit: T_{EOT} value			
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$1.3.11 - \text{data lane HS-TX from } 20 \% \text{ to} \\ 80 \% \text{ rise time } t_R \\ 1.3.12 - \text{data lane HS-TX from } 80 \% \text{ to} \\ 20 \% \text{ fall time } t_F \\ 1.3.13 - \text{data lane HS exit: } T_{\text{HS-TRAIL}} \text{ value} \\ 1.3.14 - \text{data lane HS exit: from } 30 \% \text{ to} \\ 85 \% \text{ post-EoT rise time } T_{\text{REOT}} \\ 1.3.15 - \text{data lane HS exit: } T_{\text{EOT}} \text{ value}$			
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$ 20 \% \text{ fall time } t_F \\ \hline 1.3.13 - \text{data lane HS exit: } T_{\text{HS-TRAIL}} \text{ value} \\ 1.3.14 - \text{data lane HS exit: } from 30 \% \text{ to} \\ 85 \% \text{ post-EoT rise time } T_{\text{REOT}} \\ \hline 1.3.15 - \text{data lane HS exit: } T_{\text{EOT}} \text{ value} $			
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85 % post-EoT rise time T _{REOT} 1.3.15 – data lane HS exit: T _{EOT} value			
1.3.15 – data lane HS exit: T _{EOT} value			
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			1.3.16 – data lane HS exit: T _{HS-FXIT} value

group 4 (18 tests): clock lane HS-TX	1.4.1 – clock lane HS entry: T _{LPX} value
signaling requirements	1.4.2 – clock lane HS entry: T _{CLK-PREPARE}
	value
	1.4.3 – clock lane HS entry: T _{CLK-PREPARE} +
	T _{CLK-ZERO} value
	1.4.4 – clock lane HS-TX differential
	voltages V _{OD(0)} and V _{OD(1)}
	1.4.5 – clock lane HS-TX differential
	voltage mismatch ΔV _{OD}
	1.4.6 – clock lane HS-TX single-ended
	output voltages V _{OHHS(DP)} and V _{OHHS(DN)}
	1.4.7 – clock lane HS-TX static common-
	mode voltages V _{CMTX(1)} and V _{CMTX(0)}
	1.4.8 – clock lane HS-TX static common-
	mode voltage mismatch ΔV _{CMTX(1,0)}
	1.4.9 – clock lane HS-TX dynamic
	common-level variations from 50 MHz to
	450 MHz ΔV _{CMTX(LF)}
	1.4.10 - clock lane HS-TX dynamic
	common-level variations above 450 MHz
	$\Delta V_{\text{CMTX(HF)}}$
	1.4.11 – clock lane HS-TX from 20 % to
	80 % rise time t _R
	1.4.12 – clock lane HS-TX from 80 % to
	20 % fall time t _F
	1.4.13 – clock lane HS exit: T _{CLK-TRAIL}
	value
	1.4.14 - clock lane HS exit: from 30 % to
	85 % post-EoT rise time T _{REOT}
	1.4.15 – clock lane HS exit: T _{EOT} value
	1.4.16 – clock lane HS exit: T _{HS-EXIT} value
	1.4.17 – clock lane HS clock
	instantaneous: Ul _{INST} value
	1.4.18 – clock lane HS clock delta UI:
	(ΔUI) value
group 5 (4 tests): HS-TX clock-to-data	1.5.1 – HS entry: T _{CLK-PRE} value
lane timing requirements	1.5.2 – HS exit: T _{CLK-POST} value
	1.5.3 – HS clock rising edge alignment to
	first payload bit
	1.5.4 – data-to-clock skew (T _{SKEW[TX]})

Power analysis	TI DAG®DTO 1604	" , The Date of the second of	
General description	The R&S®RTO-K31 power analysis option extends the R&S®RTO firmware with measurement functionality focused on switched mode power supplies (SMPS) and DC/DC converters.		
Input	quality	evaluation of power quality at an AC input; measures real power, apparent power, reactive power, power factor and phase angle of power, frequency, crest factor, RMS of voltage and current	
	harmonics	measures up to the 40th harmonic of the incoming line frequency; precompliance checking for IEC 61000-3-2 (A, B, C, D), RTCA DO 160, MIL-STD-1399, max. limit checks	
	inrush current	measures peak inrush current; multiple measurement zones configurable with analysis of the post-inrush behavior	
Switching/control loop	slew rate	The slope of current or voltage is measured at start and end of the switching cycle.	
	modulation	measures modulation of switching frequency and duty cycle under steady state and start-up conditions	
	dynamic on-resistance	measures resistance of the switching transistor(s) in active state	
Power path	efficiency (only for 4 channel devices) loss	measures input and output power to calculate the efficiency of an SMPS measures switching loss and conduction	
		loss of a power device	
	safe operating area (SOA)	checks violation of voltage and current limits in which a power device can operate without damage; current versus voltage view (linear or log); violation mask is user-defined and editable in linear and log-log views	
	turn on/off	measures relationship between AC and DC current, when turning the SMPS off and on	
Output	ripple	measures AC components of output voltage and current, AC RMS, frequency duty cycles, min./max./peak-to-peak amplitude	
	spectrum	FFT analysis of output, measurement of frequency peaks	
	transient response	This measurement captures the device behavior between the event of load changes and stabilization. includes peak (voltage, time), settling time, rise time, overshoot and delay	
Deskew	automated	By using the R&S®RT-ZF20 probe deskew and calibration test fixture and Rohde & Schwarz voltage and current probes, the skew between the voltage and current signal is compensated	
Reporting		automatically. easy reporting: Click to save a measurement. Report generation using user-selected test results from historical and currently-active tests. Put repeated and/or different	

MIPI RFFE triggering and decod	ling	
Protocol configuration	signal type	two channel, single-ended
-	bit rate	auto-detected, up to 26 Mbps
	auto threshold setup	assisted threshold configuration
	source (SCLK, SDATA)	any two input channels, math waveforms,
		reference waveforms, or logical channels
Trigger	trigger event setup	sequence start, sequence stop, register 0 write, register write, register read, extended register write, extended register read, extended register write long, extended register read long, error condition types
	sequence start setup	4 bit slave address; conditions =, ≠, <, ≤, >, ≥, in range, out of range
	sequence stop setup	4 bit slave address; conditions =, ≠, <, ≤, >, ≥, in range, out of range
	register 0 write setup	4 bit slave address, 7 bit data word; conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options
	register write/read	4 bit slave address, 5 bit register address, 8 bit data word; conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options
	extended register write/read	4 bit slave address; 8 bit address, byte count : 0 to 15 (inclusive), data pattern: 1 to 16 bytes (hex or binary); conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options; index: 1 to 16 selects the specific data frame byte; conditions =, ≠, <, ≤, >, ≥, in range
	extended register write long/read long	4 bit slave address, 8 bit address, byte count: 0 to 7 (inclusive), data pattern: 0 to 8 bytes (hex or binary); conditions =, ≠, <, ≤, >, ≥, in range, out of range for each of these options; index: 1 to 8 selects the specific data frame byte; conditions =, ≠, <, ≤, >, ≥, in range
	error condition	SSC error; length error, bus park error, parity error, no response, unknown sequence, minimum gap between frames: 2 ns to 100 ns maximum gap between frames:
Decode	display type	2 ns to 1 ms decoded bus, logical signal, bus + logical signal, tabulated list
	color coding data format	sequence, frame, error
Search	search event setup	hex, octal, binary, ASCII, signed, unsigned sequence start, sequence stop, register 0 write, register write, register read, extended register write, extended register read, extended register write long, extended register read long, error
	ovent cettings	condition types
	event settings	same as trigger event settings

MDIO triggering and decoding		
Protocol configuration	bit rate	up to 5 Mbps (auto-detected)
	auto threshold setup	assisted threshold configuration for MDIO triggering and decoding
	device list	associate frame address with symbolic ID
Trigger	source (clock and data)	any input channel or logical channel
	trigger event setup	start, stop, ST, OP, PHY address, register address, data
	ST setup	01 (clause 22), 00 clause 45, any
	OP setup	address, write, post read, read, any
	PHY address setup	5 bit address (hex, decimal, octal or binary); equal
	PHY register (clause 22) / device type (clause 45) setup	5 bit value (hex, decimal, octal or binary); equal
	data (clause 22) / data / address (clause 45)	16 bit value (hex, decimal, octal or binary); equal
Decode	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	display type	decoded bus, logical signal, bus + logical signal, tabulated list
	color coding	frame, PHY address, PHY register, address, data, turnaround
	PHYAD/PRTAD	symbolic names for user defined addresses
	address/data field format	hex, decimal, octal, binary, ASCII
Search	source (clock and data)	any input channel, math waveform, reference waveform, logical channel
	search event setup	start, stop, ST, OP, PHY address, register address, data
	event settings	same as trigger event settings

USB 1.0/1.1/2.0/HSIC triggering Protocol configuration		single anded differential	
Protocol configuration	signal type	single-ended, differential	
	protocol type bit rate	low, full, high speed and HSIC standard bit rates (1.5/12/480 Mbit/s)	
	source	any input channel	
	probe type	any input chariner	
	for low and full speed	single anded probe	
	for high speed	single-ended probe differential probe (R&S®ZDx)	
	for HSIC	single-ended probe(R&S®ZSx)	
	auto threshold setup	assisted threshold configuration for USB	
	auto tinesnoia setup	triggering and decoding	
Trigger	trigger event setup	start of packet, end of packet, PID token (IN, OUT, SETUP, SOF), PID data (Datat Data1, Data2 ⁵ , MData ⁵), PID handshake (ACK, NAK, STALL, NYET ⁵), PID specia (PRE ⁶ , ERR ⁵ , SPLIT ⁵ , PING ⁵); bus stat (reset ⁶ , resume ⁶ , suspend ⁶); error condition	
	address, endpoint and frame setup SC, port, SEU, ET check (SPLIT) ⁶	condition =, ≠, ≥, ≤, in range, out of range	
	data setup ⁶	data pattern up to 4 byte (hex, decimal, octal, binary or ASCII), bit separately configurable (1, 0 or don't care); condition =, ≠; position based or window based triggering (first occurrence in packet payload)	
	error condition ⁶	any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error ⁶ and glitching error	
Decode	source	any input channel, math waveform	
	display type	decoded bus, logical signal, bus + logical signal, tabulated list	
	color coding	packet identifier, payload length, frame, address, endpoint, data payload, CRC5, CRC16, error condition	
	data format	hexadecimal, decimal, octal, binary, ASCII, unsigned	
Search	search event setup	combination of start of packet, PID token (IN, OUT, SETUP, SOF), PID data (Data(Data1, Data2 ⁵ , MData ⁵), PID handshake (ACK, NAK, STALL, NYET ⁵), PID specia (PRE ⁶ , ERR ⁵ , SPLIT ⁵ , PING ⁵); error condition (any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error ⁶ and glitching error)	
	address, endpoint and frame setup SC, port, SEU, ET check (SPLIT)	condition =, ≠, ≥, ≤, in range, out of range	
	data setup	data pattern up to 4 byte (hex, decimal, octal, binary or ASCII), bit separately configurable (1, 0 or don't care); condition =, ≠; position based or window based triggering (first occurrence in packet payload)	
	error condition	any error, PID error, CRC5 error, CRC16 error, bit stuffing error, unexpected PID, SE1 error ⁶ and glitching error	

 $^{^{\}rm 5}$ $\,$ Only available in high speed and HSIC.

⁶ Only available in low and full speed.

Ordering information

Designation	Туре	Order No.
Base unit (including standard accessories: 500 MHz passive probe (10:1) per channel,	accessories bag, quic	k start guide,
CD with manual, power cord)		
Digital Oscilloscope		
600 MHz, 10 Gsample/s, 20/40 Msample, 2 channels	R&S®RTO1002	1316.1000.02
600 MHz, 10 Gsample/s, 20/80 Msample, 4 channels	R&S®RTO1004	1316.1000.04
1 GHz, 10 Gsample/s, 20/40 Msample, 2 channels	R&S®RTO1012	1316.1000.12
1 GHz, 10 Gsample/s, 20/80 Msample, 4 channels	R&S®RTO1014	1316.1000.14
2 GHz, 10 Gsample/s, 20/40 Msample, 2 channels	R&S®RTO1022	1316.1000.22
2 GHz, 10 Gsample/s, 20/80 Msample, 4 channels	R&S®RTO1024	1316.1000.24
4 GHz, 20 Gsample/s, 20/80 Msample, 4 channels	R&S®RTO1044	1316.1000.44
Hardware options (plug-in)		
Mixed Signal Option, 400 MHz for R&S®RTO with order no. 1316.1000.xx	R&S®RTO-B1	1304.9901.03
Mixed Signal Option, 400 MHz for R&S®RTO with order no. 1304.6002.xx	R&S®RTO-B1	1304.9901.02
OCXO 10 MHz	R&S®RTO-B4	1304.8305.02
GPIB Interface, for R&S®RTO with order no. 1316.1000.xx	R&S®RTO-B10	1304.8311.03
GPIB Interface, for R&S®RTO with order no. 1304.6002.xx	R&S®RTO-B10	1304.8311.02
Solid State Disk (instruments with operating system Windows XP embedded)	R&S®RTO-B18	1317.6993.02
Solid State Disk (instruments with operating system Windows 7 embedded)	R&S®RTO-B18	1317.6993.03
Replacement Hard Disk, incl. firmware (instruments with operating system Windows XF	R&S®RTO-B19	1304.8328.02
embedded)		
Replacement Hard Disk, incl. firmware (instruments with operating system Windows XF	P R&S®RTO-B19	1304.8328.03
embedded)		
Memory Upgrade, 50 Msample per channel	R&S®RTO-B101	1304.8428.02
Memory Upgrade, 100 Msample per channel	R&S®RTO-B102	1304.8434.02
Memory Upgrade, 200 Msample per channel (instruments with operating system	R&S®RTO-B103	1304.8440.02
Windows 7 embedded)		
Memory Upgrade, 400 Msample per channel (instruments with operating system	R&S®RTO-B104	1304.8457.02
Windows 7 embedded)		
Bandwidth upgrades ⁷		
Upgrade of R&S®RTO1002/4 oscilloscopes to 1 GHz bandwidth, incl. calibration	R&S®RTO-B200	1316.1323.02
Upgrade of R&S®RTO1002/4 oscilloscopes to 2 GHz bandwidth, incl. calibration	R&S®RTO-B201	1316.1330.02
Upgrade of R&S®RTO1004 oscilloscope to 4 GHz bandwidth, incl. calibration	R&S®RTO-B202	1316.1346.02
Upgrade of R&S®RTO1012/4 oscilloscopes to 2 GHz bandwidth, incl. calibration	R&S®RTO-B203	1316.1352.02
Upgrade of R&S®RTO1014 oscilloscope to 4 GHz bandwidth, incl. calibration	R&S®RTO-B204	1316.1369.02
Upgrade of R&S®RTO1024 oscilloscope to 4 GHz bandwidth, incl. calibration	R&S®RTO-B205	1316.1375.02
Upgrade of operating system from Windows XP embedded to Windows 7 embedded		1317.7048.02
Software options		
Serial triggering and decoding		
I ² C/SPI Serial Decoding	R&S®RTO-K1	1304.8511.02
UART/RS-232/RS-422/RS-485 Serial Decoding	R&S®RTO-K2	1304.8528.02
CAN/LIN Serial Triggering and Decoding	R&S®RTO-K3	1304.8534.02
FlexRay™ Serial Triggering and Decoding	R&S®RTO-K4	1304.8540.02
I ² S Serial Triggering and Decoding	R&S®RTO-K5	1317.3620.02
MIL-STD-1553 Serial Triggering and Decoding	R&S®RTO-K6	1317.7419.02
ARINC 429 Serial Triggering and Decoding	R&S®RTO-K7	1317.7425.02
CAN FD Serial Triggering and Decoding	R&S®RTO-K9	1325.9881.02
MIPI RFFE Serial Triggering and Decoding	R&S®RTO-K40	1325.9900.02
MDIO Serial Triggering and Decoding	R&S®RTO-K40	1326.0713.02
USB 1.0/1.1/2.0/HSIC Serial Triggering and Decoding	R&S®RTO-K60	1320.6690.02
Compliance tests	Nas K10-N00	1320.0090.02
USB 2.0 Compliance Test	R&S®RTO-K21	1317.4103.02
	R&S®RTO-K21	
Ethernet Compliance Test		1317.4678.02
Ethernet 10G Compliance Test	R&S®RTO-K23	1320.6261.02
BroadR-Reach Compliance Test	R&S®RTO-K24	1320.6684.02
D-PHY Compliance Test	R&S®RTO-K26	1317.5668.02
Analysis	D 0 0 0 0 7 0 1 1 1 1	1017 0077 55
I/Q Software Interface	R&S®RTO-K11	1317.2975.02
Jitter Analysis	R&S®RTO-K12	1317.4690.02
	R&S®RTO-K13	1317.4703.02
Clock Data Recovery		
Clock Data Recovery High Definition Mode Power Analysis	R&S®RTO-K17 R&S®RTO-K31	1326.0536.02 1317.5739.02

⁷ The bandwidth upgrade is performed at a Rohde & Schwarz service center, where the oscilloscope will also be calibrated.

Version 18.00, November 2014

Designation	Туре	Order No.
Probes		
500 MHz, passive, 10:1, 1 MΩ, 9.5 pF, max. 400 V	R&S®RT-ZP10	1409.7550.00
400 MHz, passive, high-voltage, 100:1, 50 MΩ, 7.5 pF, 1 kV (RMS)	R&S®RT-ZH10	1409.7720.02
400 MHz, passive, high-voltage, 1000:1, 50 MΩ, 7.5 pF, 1 kV (RMS)	R&S®RT-ZH11	1409.7737.02
8.0 GHz, passive, transmission line, 10:1, 500 Ω, 0.3 pF, 20 V (RMS)	R&S®RT-ZZ80	1409.7608.02
1.0 GHz, active, 1 MΩ 0.8 pF	R&S®RT-ZS10E	1418.7007.02
1.0 GHz, active, 1 MΩ 0.8 pF, R&S®ProbeMeter, micro button	R&S®RT-ZS10	1410.4080.02
1.5 GHz, active, 1 MΩ 0.8 pF, R&S®ProbeMeter, micro button	R&S®RT-ZS20	1410.3502.02
3.0 GHz, active, 1 MΩ 0.8 pF, R&S®ProbeMeter, micro button	R&S®RT-ZS30	1410.4309.02
6.0 GHz, active, 1 MΩ 0.3 pF, R&S®ProbeMeter, micro button	R&S®RT-ZS60	1418.7307.02
100 MHz, high-voltage, active, differential, 8 MΩ 3.5 pF, 1 kV (RMS) (CAT III)	R&S®RT-ZD01	1422.0703.02
1.5 GHz, active, differential, 1 MΩ 0.6 pF, R&S®ProbeMeter, micro button	R&S®RT-ZD20	1410.4409.02
3.0 GHz, active, differential, 1 MΩ 0.6 pF, R&S®ProbeMeter, micro button	R&S®RT-ZD30	1410.4609.02
4.5 GHz, active, differential, 1 MΩ 0.4 pF, R&S®ProbeMeter, micro button	R&S®RT-ZD40	1410.5205.02
10 MHz, current, AC/DC, 0.01 V/A, 150 A (RMS)	R&S®RT-ZC10	1409.7750.02
100 MHz, current, AC/DC, 0.1 V/A, 30 A (RMS)	R&S®RT-ZC20	1409.7766.02
Probe accessories		·
Accessory Set for R&S®RT-ZP10 passive probe (2.5 mm probe tip)	R&S®RT-ZA1	1409.7566.00
Spare Accessory Set for R&S®RT-ZS10/10E/20/30	R&S®RT-ZA2	1416.0405.02
Pin Set for R&S®RT-ZS10/10E/20/30	R&S®RT-ZA3	1416.0411.02
Mini Clips	R&S®RT-ZA4	1416.0428.02
Micro Clips	R&S®RT-ZA5	1416.0434.02
Lead Set	R&S®RT-ZA6	1416.0440.02
Pin Set for R&S®RT-ZD20/30	R&S®RT-ZA7	1417.0609.02
Pin Set for R&S®RT-ZD40	R&S®RT-ZA8	1417.0867.02
SMA Adapter	R&S®RT-ZA10	1416.0457.02
Probe Power Supply	R&S®RT-ZA13	1409.7789.02
Accessories		
Front Cover, for R&S®RTO digital oscilloscopes	R&S®RTO-Z1	1317.6970.02
Soft Case, for R&S®RTO digital oscilloscopes and accessories	R&S®RTO-Z3	1304.9118.02
Transit Case, for R&S®RTO/RTE digital oscilloscopes and accessories	R&S®RTO-Z4	1317.7025.02
Probe Pouch, for R&S®RTO digital oscilloscopes	R&S®RTO-Z5	1317.7031.02
USB 2.0 Compliance Test Fixture Set	R&S®RT-ZF1	1317.3420.02
Ethernet Compliance Test Fixture Set	R&S®RT-ZF2	1317.5522.02
Probe Deskew and Calibration Test Fixture	R&S®RT-ZF20	1800.0004.02
19" Rackmount Kit, for R&S®RTO digital oscilloscopes with 6 HU	R&S®ZZA-RTO	1304.8286.02

Service options		
Extended Warranty, one year	R&S®WE1	Please contact your
Extended Warranty, two years	R&S®WE2	local Rohde & Schwarz
Extended Warranty, three years	R&S®WE3	sales office.
Extended Warranty, four years	R&S®WE4	
Extended Warranty with Calibration Coverage, one year	R&S®CW1	
Extended Warranty with Calibration Coverage, two years	R&S®CW2	
Extended Warranty with Calibration Coverage, three years	R&S®CW3	
Extended Warranty with Calibration Coverage, four years	R&S®CW4	

Extended warranty with a term of one to four years (WE1 to WE4)

Repairs carried out during the contract term are free of charge ⁸. Necessary calibration and adjustments carried out during repairs are also covered. Simply contact the forwarding agent we name; your product will be picked up free of charge and returned to you in top condition a couple of days later.

Extended warranty with calibration (CW1 to CW4)

Enhance your extended warranty by adding calibration coverage at a package price. This package ensures that your Rohde & Schwarz product is regularly calibrated, inspected and maintained during the term of the contract. It includes all repairs ⁸ and calibration at the recommended intervals as well as any calibration carried out during repairs or option upgrades.

⁸ Excluding defects caused by incorrect operation or handling and force majeure. Wear-and-tear parts are not included.

Service that adds value

- Uncompromising qualityLong-term dependability

About Rohde & Schwarz

The Rohde & Schwarz electronics group is a leading supplier of solutions in the fields of test and measurement, broadcasting, secure communications, and radiomonitoring and radiolocation. Founded more than 80 years ago, this independent global company has an extensive sales network and is present in more than 70 countries. The company is headquartered in Munich, Germany.

Sustainable product design

- Environmental compatibility and eco-footprint
- Energy efficiency and low emissions
- Longevity and optimized total cost of ownership

Certified Quality Management ISO 9001

Certified Environmental Management ISO 14001

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